



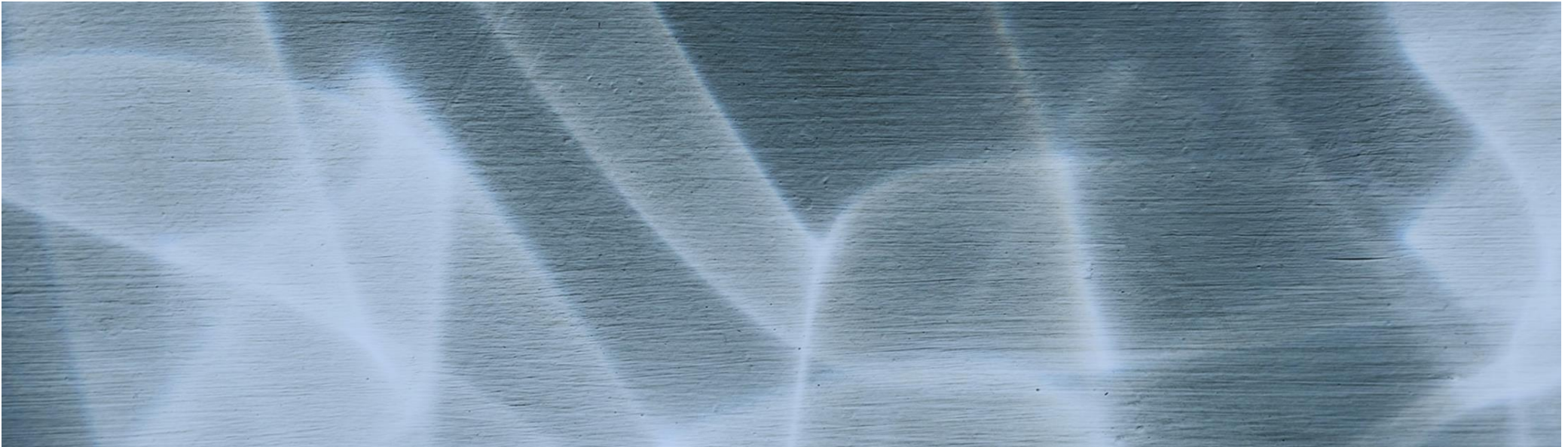
Otsuka

Otsuka Electronics Korea Co., Ltd.

COMPANY PROFILE

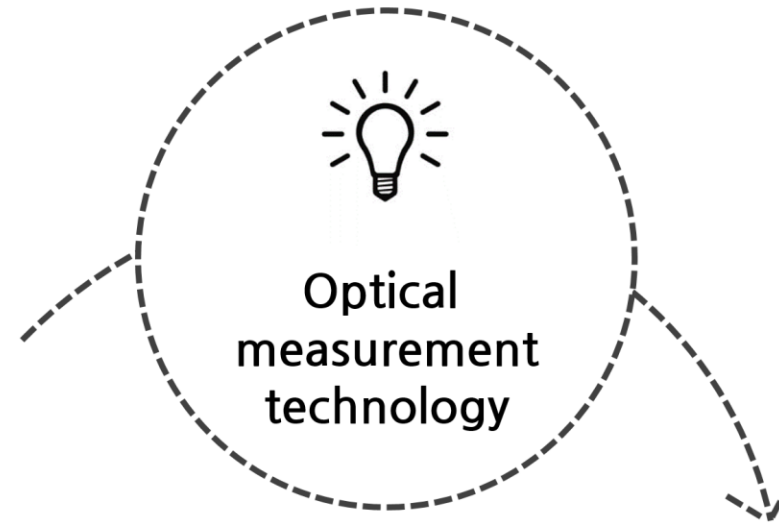
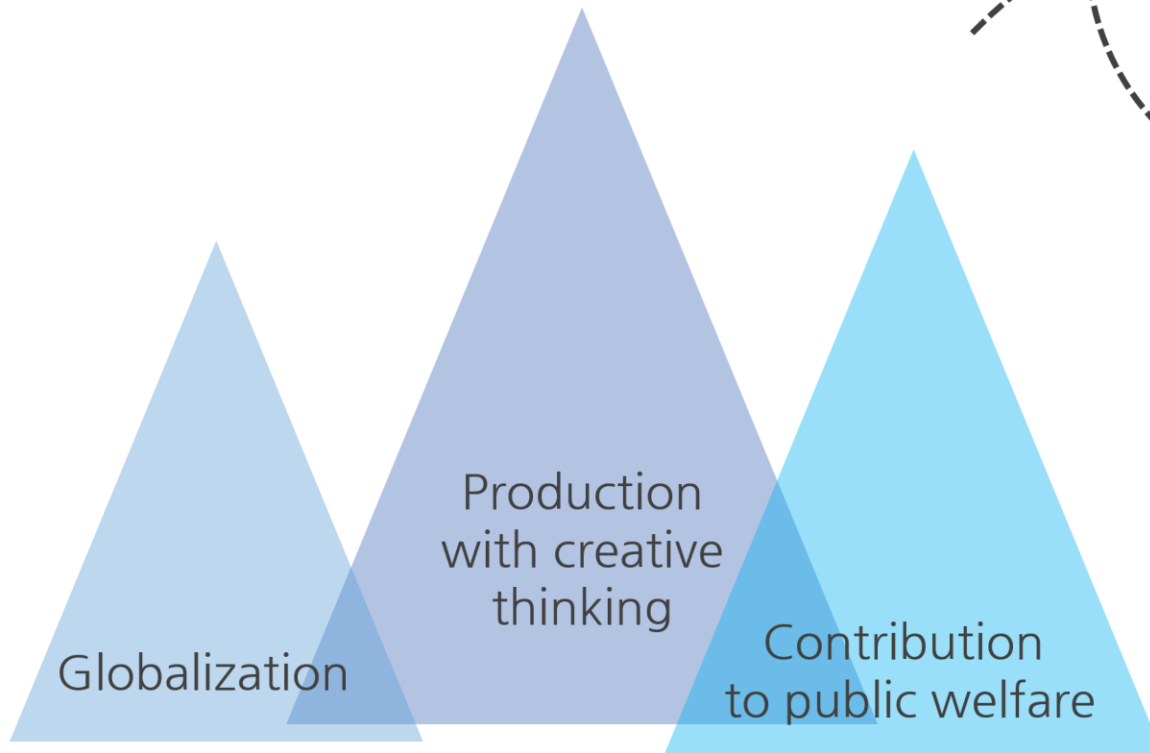


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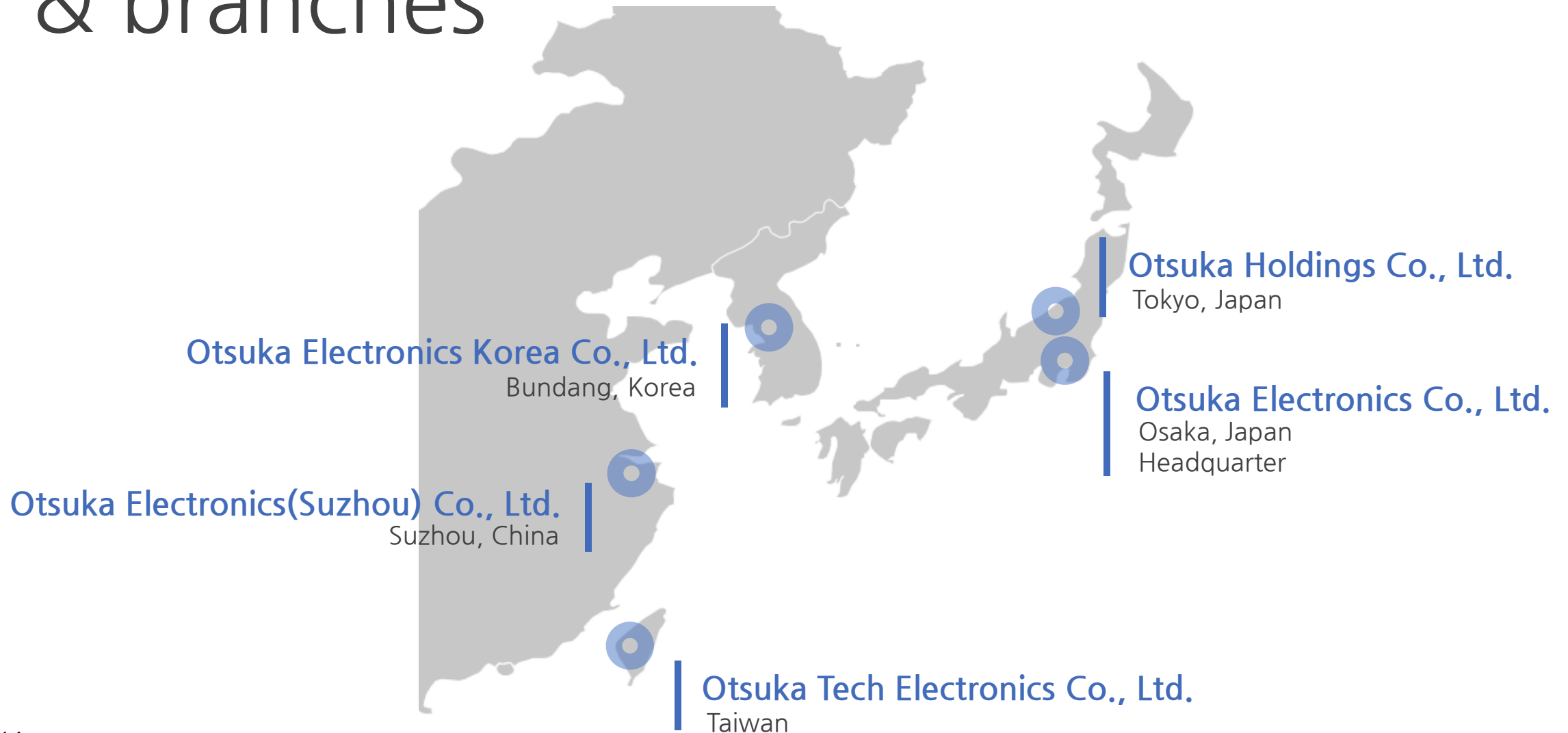
ABOUT OUR COMPANY

Corporate philosophy



“Otsuka-people
creating new products
for better health and life
worldwide.”

Headquarters & branches



Profile



CEO

Jeong-Hyun Yu



Founded

In August 2003



Located in

41, Seongnam-daero 925beon-gil,
Bundang-gu, Seongnam-si, Gyeonggi-do,
Republic of Korea



Employee

42 people



Sales

USD 10 million (2018)



Sales of Otsuka Holdings

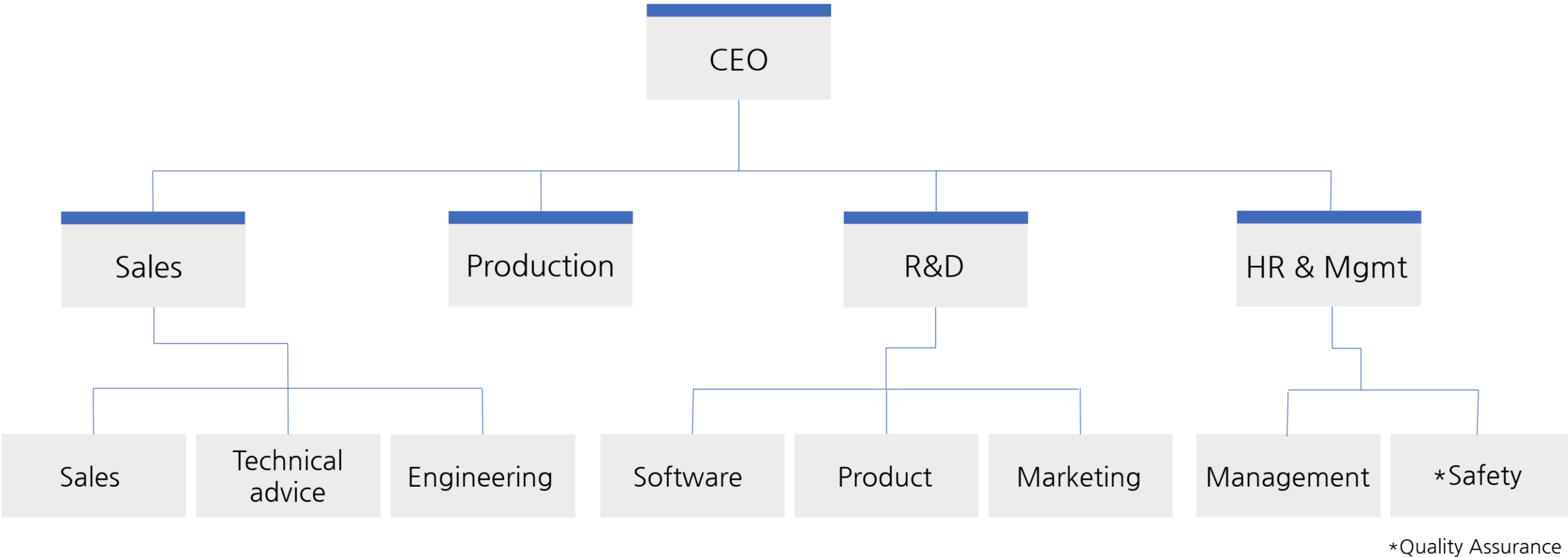
USD 10 billion (2018)



Business

optical instruments,
industrial automation
instruments, biomaterial
analyzers, materials
analyzers for new
materials

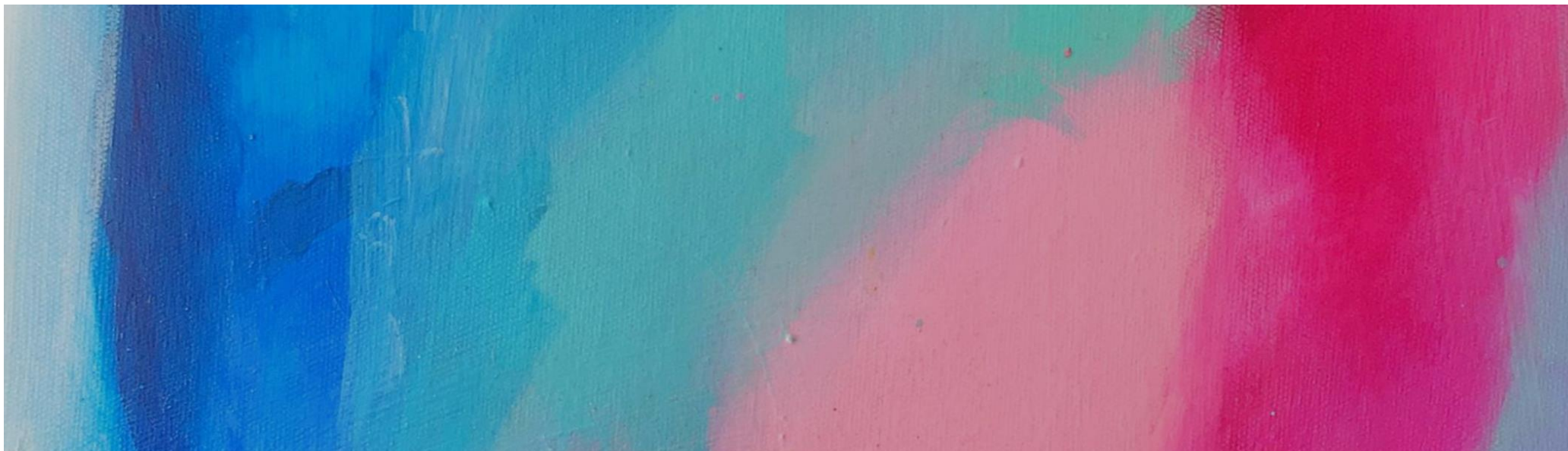
Organization chart



*Quality Assurance

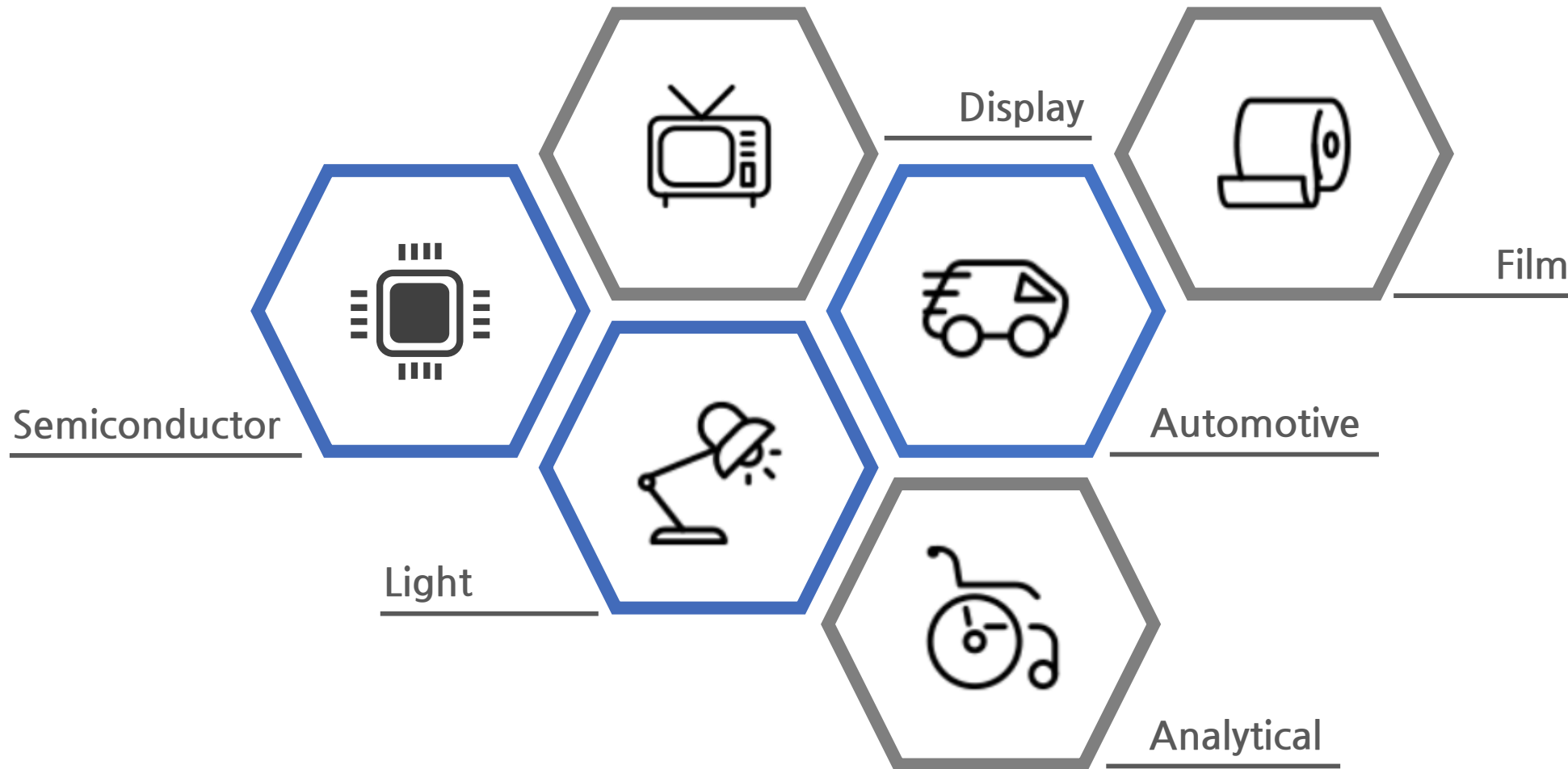


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PRODUCTS

Product line



Display evaluation



Imaging photometer

HS-1000H

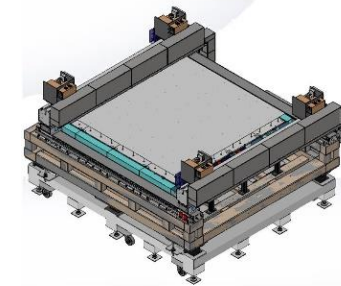
- Luminance uniformity evaluation
- High speed(1.5 sec. per frame)
- 300% of time reduction
- Large area measurement



Color filter spectral Inspection system

LCF

- FPD manufacturing process
- Fully automated pattern matching
- Color filter evaluation
- CF, OC, CS thickness measurement



Sheet resistance

RS

- Contact / non-contact RS measurement
- Low / high resistance measurement
- Conductive materials and films
- Less than 1.5% CV (reproducibility)

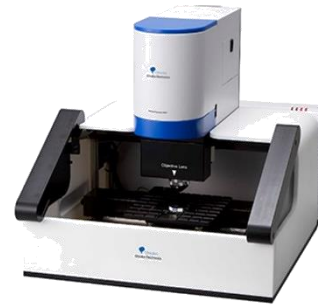
Semiconductor evaluation



Si wafer thickness monitoring system

SF-3 series

- Real-time measurement
- Si wafer thickness
- CMP, backside grinding
- Non-contact
- Non-destructive



Microspectrophotometer

OPTM(UV SR) series

- From UV to NIR
- Non-contact
- Non-destructive
- High speed(less than 1 sec.)
- Automatic mapping



Spectro ellipsometer

FE-5000 series

- Ellipsometry measurement
- From UV to visible light
- Automatic angle adjusting mechanism
- Automatic mapping
- Thickness & optical constant(n , k) of ultra thin film

Film evaluation



Array spectrometer

MCPD series

- From UV to NIR
- Compact and light
- Wide integration time range
- Stray light correction function



Retardation film & material evaluation system

RETS 100

- Polarization characteristics
- Retardation and axis of each layer
- Multi-layered sample
- Non-destructive



LCD cell gap measurement

RETS series

- Polarization optical system
- LCD cell gap
- Empty cell gap
- Compatible with small to large sizes



High speed retardation measurement

RE-200

- High accuracy
- High speed (less than 0.1 sec.)
- Easier measurement with less steps
- Low retardation from 0nm

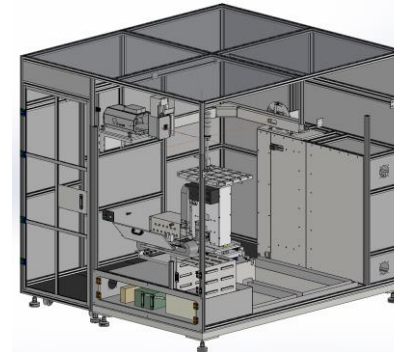
Automotive evaluation



Headlamp aimer

HLA

- Vehicle production factory
- All types of light source
- End of line / audit station
- Quick and repeatable aiming
- Floor / gantry / portable types



Headlamp aiming photometric tester

HLT600

- Headlamp assembly line
- Various lamp types(multi LED headlamp)
- CAN / LIN interfaces
- Customization available



Goniophotometric tester

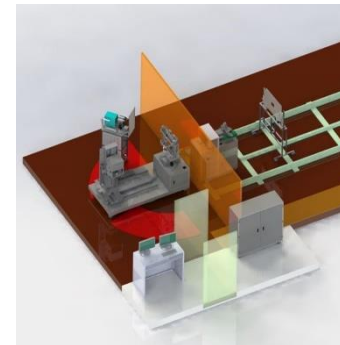
RH600(near field)

- LiDAR intensity evaluation
- Various simulation results with a single measurement
- No darkroom required

Camera monitor system module tester

CMS

- Full automation system
- Test judgement - pass or fail
- Camera and monitor instead of a mirror



Light measurement



Luminous intensity measurement system

AL-1000

- Brightness of micro LED
- High sensitive spectrometer
- Precise measurement of ultra-low light from $1\mu\text{cd}$



High sensitive spectroradiometer

HS-1000

- High speed(20msec. for continuous mode)
- Wide luminance range
- Polarization error reduction to $< 1\%$



High speed near field goniophotometer

RH series

- Light distribution evaluation
- Various simulation results with a single measurement
- No darkroom required
- No sample-rotation required



Total luminous flux measurement system

HM/FM series

- Wide dynamic range
- Self absorption correction function
- Doubled sensitivity
- Shadow effect elimination

Analytical



Multi-sample nanoparticle size measurement system

nanoSAQLA

- Multiple samples(5ea) at one time
- High speed(1 min. for measurement)
- Temperature gradient function
- Compact and light
- Best with Autosampler



Particle size, zeta potential, molecular weight analyzer

ELSZ-2000 series

- Zeta potential of solid sample measurable
- Concentrated / dilute samples
- Colored / black samples
- Temperature gradient function
- Melting point and phase transition point analysis



Quantum efficiency measurement system

QE-2000 series

- Various forms of samples
- Low stray light effect
- Accurate measurement of efficiency (re-excitation eliminating function)
- Easy cell loading / unloading



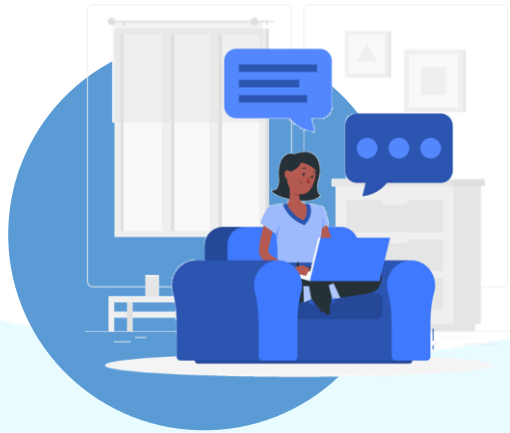
High sensitivity NIR quantum efficiency measurement system

QE-5000

- Singlet oxygen detection
- Precise measurement of ultra-low quantum efficiency
- Various forms of samples
- Liquid-nitrogen-free cooling detector

Our products are limitless

Make innovation with us.



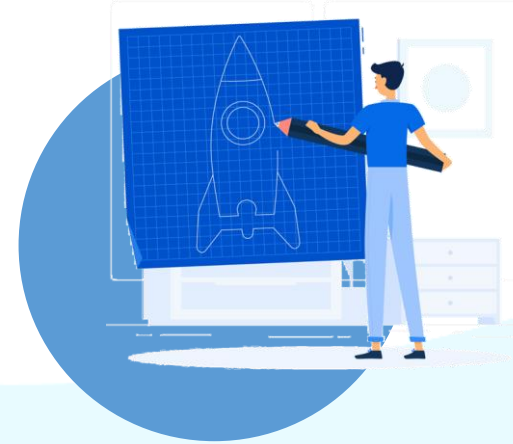
1. Inquiry

Do not hesitate to contact us and let us know the detail specifications to make your ideal product



2. Innovation

Based on our long time experiences and knowledge at optical technology, we map out an innovative product just for you



3. Production

Our professional technicians start a production as planned

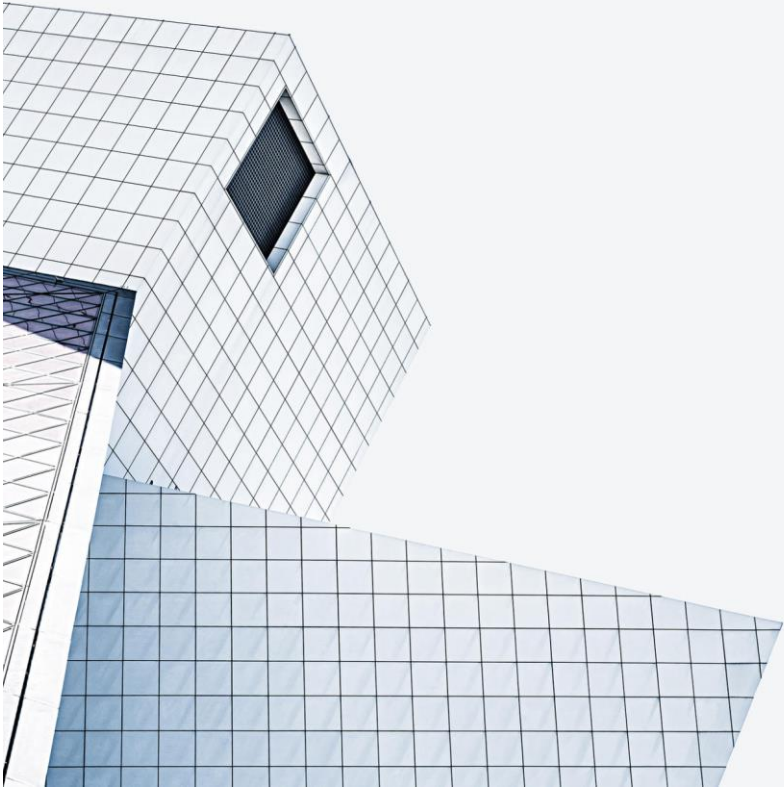


4. Tah-dah!

The product meeting your demand has been created

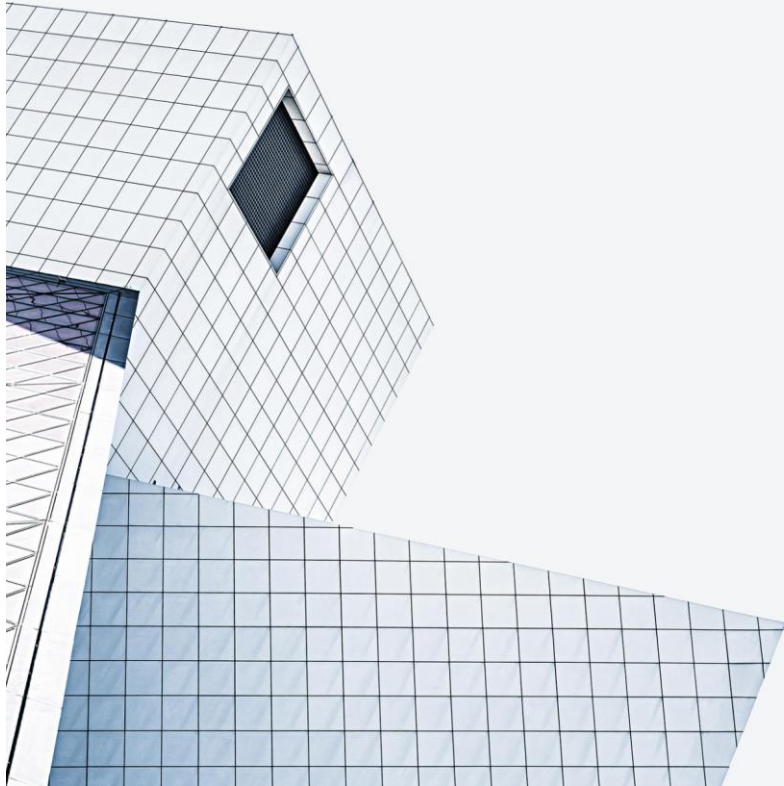
References

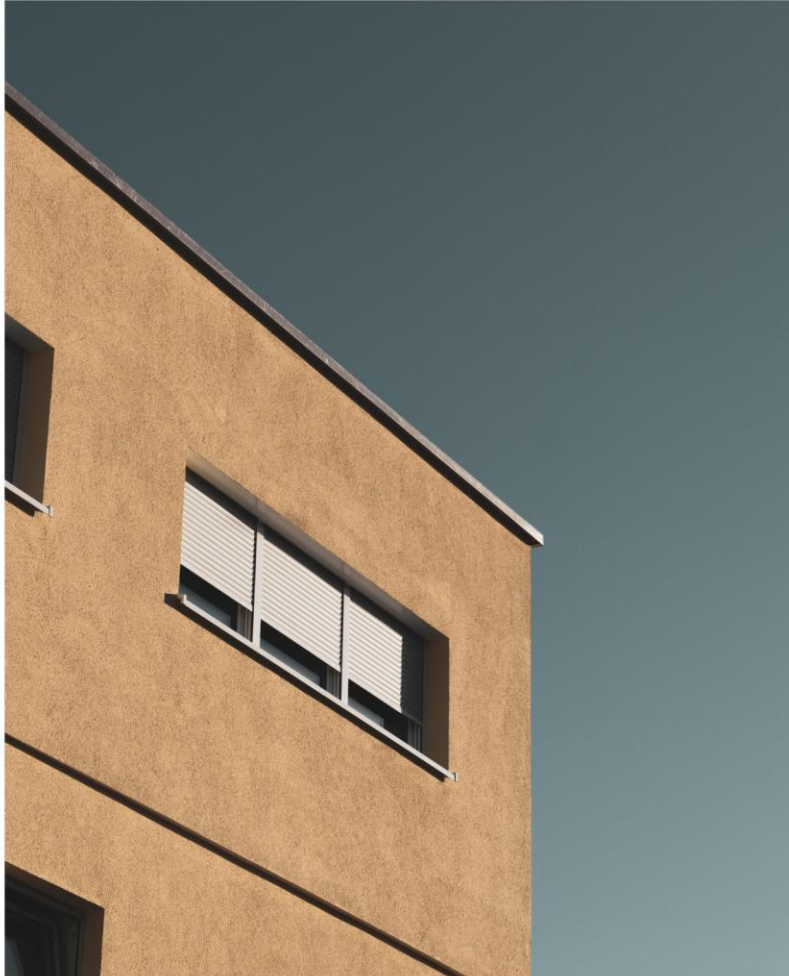
> COMPANIES



References

> LABS & UNIV.





THANK YOU



CONTACT

Otsuka Electronics Korea Co., Ltd.
6F, Fine Venture Bldg. 41, Seongnam-daero 925beon-gil,
Bundang-gu, Seongnam-si, Gyeonggi-do, South Korea
T. +82.31.766.8411
E. inquiry@otsukael.co.kr